Supporting Information

## One-step preparation of N, O co-doped 3D hierarchically porous carbon derived from soybean dregs for highperformance supercapacitors

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## Tables

Table S1 The elemental contents of all samples obtained from XPS analysis.



**Figure S1** GCD curves of carbon paper, N-O-HPC-0, N-O-HPC-1, N-O-HPC-2, and N-O-HPC-3 at the current density of 2 A g<sup>-1</sup>.

N-O-HPC-0	N-O-HPC-1	N-O-HPC-2	N-O-HPC-3
84.4	86.1	89	89.1
10.1	9	6.2	6.1
5.5	4.9	4.8	4.8
0.54	0.55	0.77	0.79
	N-O-HPC-0 84.4 10.1 5.5 0.54	N-O-HPC-0         N-O-HPC-1           84.4         86.1           10.1         9           5.5         4.9           0.54         0.55	N-O-HPC-0         N-O-HPC-1         N-O-HPC-2           84.4         86.1         89           10.1         9         6.2           5.5         4.9         4.8           0.54         0.55         0.77

**Table S1** The elemental contents of all samples obtained from XPS analysis.